

TOSHIBA Diode Silicon Epitaxial Schottky Barrier Type

HN2S03FU

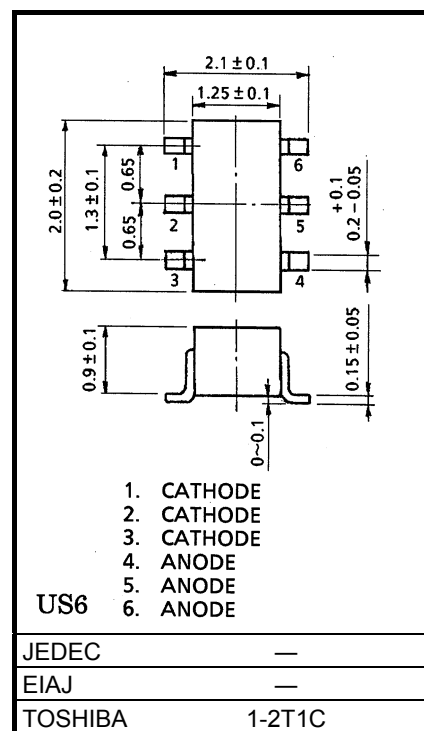
High Speed Switching Application

Unit: mm

- HN2S03FU is composed of 3 independent diodes.
- Low forward voltage : $V_F(3) = 0.50V$ (typ.)
- Low reverse current : $I_R = 0.5\mu A$ (max)
- Small total capacitance : $C_T = 3.9pF$ (typ.)

Absolute Maximum Ratings ($T_a = 25^\circ C$)

Characteristic	Symbol	Rating	Unit
Maximum (peak) reverse Voltage	V_{RM}	25	V
Reverse voltage	V_R	20	V
Maximum (peak) forward current	I_{FM}	100 *	mA
Average forward current	I_O	50 *	mA
Surge current (10ms)	I_{FSM}	1 *	A
Power dissipation	P	200 **	mW
Junction temperature	T_j	125	$^\circ C$
Storage temperature range	T_{stg}	-55~125	$^\circ C$
Operating temperature range	T_{opr}	-40~110	$^\circ C$



JEDEC	—
EIAJ	—
TOSHIBA	1-2T1C

Weight: 6.2mg(Typ.)

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

* : This is absolute maximum rating of single diode (Q1 or Q2 or Q3).

In the case of using 2 or 3 diodes, the absolute maximum ratings per diodes is 75 % of the single diode one.

** :Total rating

Electrical Characteristics (Q1, Q2, Q3 Common, $T_a = 25^\circ C$)

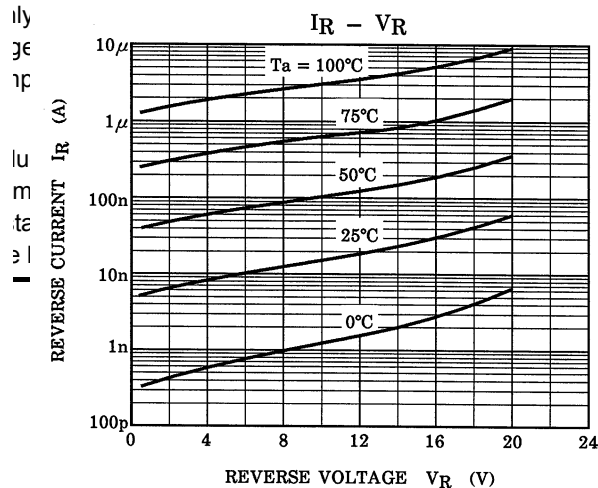
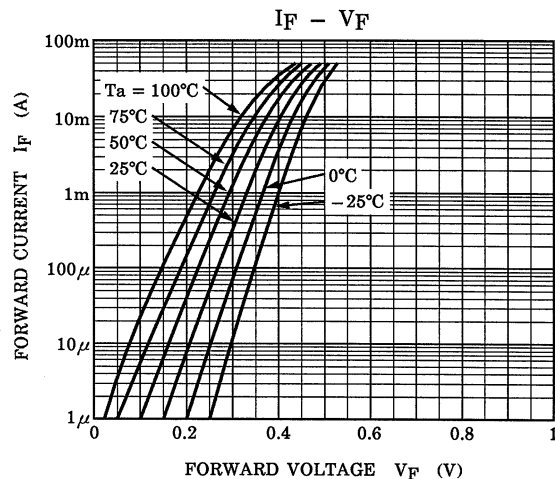
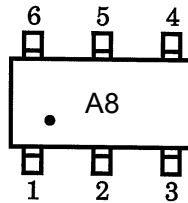
Characteristic	Symbol	Test Circuit	Test Condition	Min	Typ.	Max	Unit
Forward voltage	$V_F(1)$	—	$I_F = 1mA$	—	0.33	—	V
	$V_F(2)$	—	$I_F = 5mA$	—	0.38	—	
	$V_F(3)$	—	$I_F = 50mA$	—	0.50	0.55	
Reverse current	I_R	—	$V_R = 20V$	—	—	0.5	μA
Total capacitance	C_T	—	$V_R = 0, f = 1MHz$	—	3.9	—	pF

stress. It is the responsibility of the buyer, when utilizing TOSHIBA products, to comply with the standards of safety in making a safe design for the entire system, and to avoid situations in which a malfunction or failure of such TOSHIBA products could cause loss of human life, bodily injury or damage to property.

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For designs, please ensure that TOSHIBA products are used within specified operating conditions as set forth in the most recent TOSHIBA products specifications. Also, please keep in mind the precautions and conditions set forth in the "Handling Guide for Semiconductor Devices," or "TOSHIBA Semiconductor Reliability Handbook" etc.

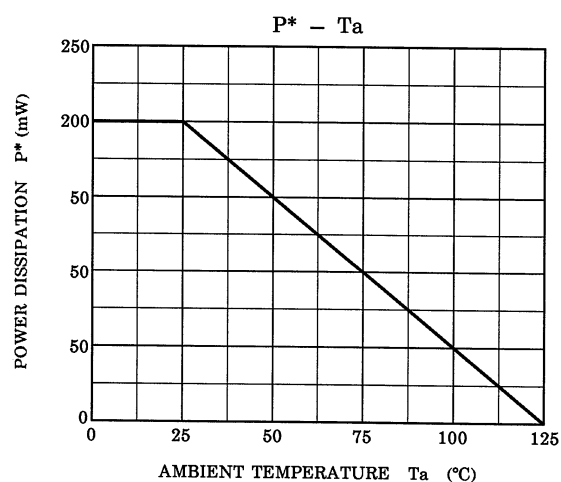
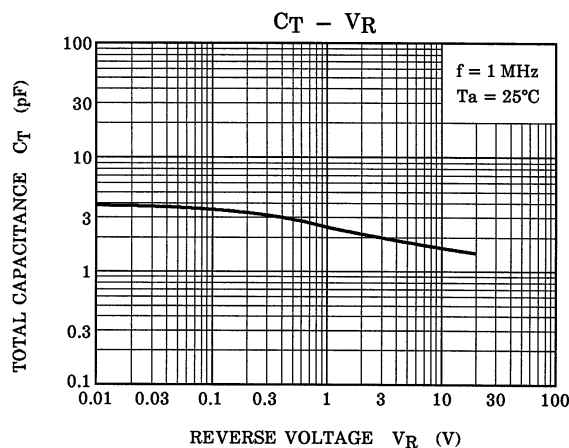
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- The products described in this document shall not be used or embedded to any downstream products of which the manufacture, use and/or sale are prohibited under any applicable laws and regulations.



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Pin Assignment (Top View)

Marking



* : Total Rating

